

# FNK N-Channel Enhancement Mode Power MOSFET

### **Description**

The FNK 03N09M uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

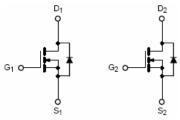
- V<sub>DS</sub> =30V,I<sub>D</sub> =18A
  - $R_{DS(ON)} < 9 \text{ m}\Omega @ V_{GS}=10V$

 $R_{DS(ON)}$  <15 m  $\Omega$  @  $V_{GS}$ =4.5V

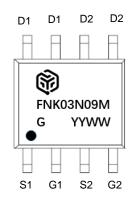
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current

### **Application**

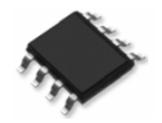
- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



**Marking and pin Assignment** 



SOP-8 top view

### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNK03N09M	FNK03N09M	SOP-8	Ø330mm	12mm	

# Absolute Maximum Ratings (T<sub>A</sub>=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage	V <sub>GS</sub>	±20	V	
Drain Current-Continuous	I <sub>D</sub>	18	А	
Drain Current-Continuous(T <sub>C</sub> =100 °C)	I <sub>D</sub> (100℃)	8	Α	
Pulsed Drain Current	I <sub>DM</sub>	72	Α	
Maximum Power Dissipation	P <sub>D</sub>	1.25	W	
Operating Junction and Storage Temperature Range	$T_{J}, T_{STG}$	-55 To 150	$^{\circ}\!\mathbb{C}$	

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{ hetaJA}$	100	°C/W

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Electrical Characteristics (T<sub>A</sub>=25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	30		-	V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA	
On Characteristics (Note 3)							
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250μA	1.0	1.6	2.5	V	
		$V_{GS}$ =10V, I $_{D}$ =10A	-	8.7	9		
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A	-	11.8	15	5 mΩ	
		V <sub>GS</sub> =2.5 V,I <sub>D</sub> =6A	<sub>D</sub> =6A		26	į	
Dynamic Characteristics (Note4)			•				
Input Capacitance	C <sub>lss</sub>	\/ -45\/\/ -0\/	-	950	-	PF	
Output Capacitance	Coss	$V_{DS}$ =15V, $V_{GS}$ =0V, F=1.0MHz	-	200	-	PF	
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0IVID2	-	180	-	PF	
Switching Characteristics (Note 4)							
Turn-on Delay Time	t <sub>d(on)</sub>		-	8	-	nS	
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =10 $V$ , $I_{D}$ =1 $A$	-	9	-	nS	
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GEN}$ =4.5 $V$ , $R_G$ =6 $\Omega$	-	15	-	nS	
Turn-Off Fall Time	t <sub>f</sub>		-	4	-	nS	
Total Gate Charge	$Q_g$	V <sub>DS</sub> =10V,I <sub>D</sub> =3A,	-	10	-	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}=10V,I_{D}=3A,$ $V_{GS}=4.5V$	-	1.5	-	nC	
Gate-Drain Charge	$Q_{gd}$	v <sub>GS</sub> -4.5v	-	1.6	-	nC	
Drain-Source Diode Characteristics			·				
Diode Forward Voltage (Note 3)	$V_{SD}$	V <sub>GS</sub> =0V,I <sub>S</sub> =1.7A	-	-	1.2	V	
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	6	Α	

#### Notes:

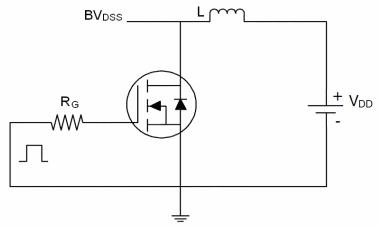
- $\textbf{1.} \ \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature.}$
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

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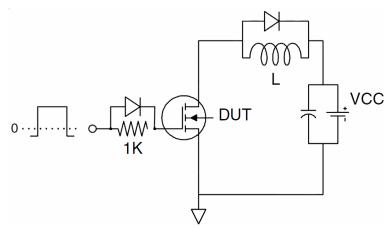


# **Test Circuit**

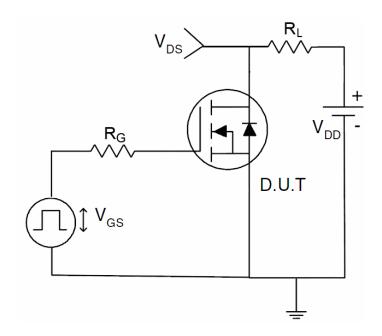
# 1) E<sub>AS</sub> Test Circuits



# 2) Gate Charge Test Circuit:



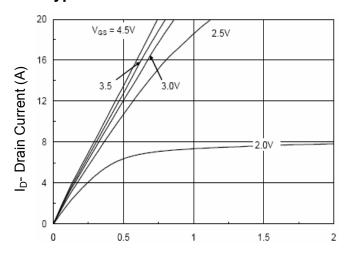
# 3) Switch Time Test Circuit:



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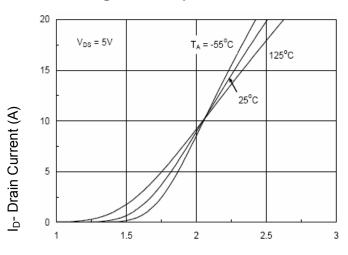


# **Typical Electrical and Thermal Characteristics (Curves)**



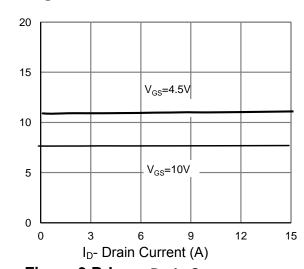
Vds Drain-Source Voltage (V)

**Figure 1 Output Characteristics** 



Vgs Gate-Source Voltage (V)

**Figure 2 Transfer Characteristics** 



Rdson On-Resistance(Ω)

Figure 3 Rdson- Drain Current

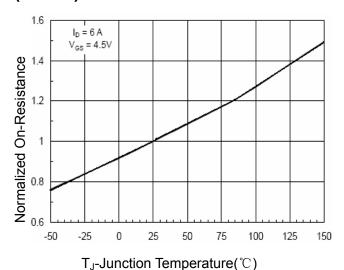


Figure 4 Rdson-JunctionTemperature

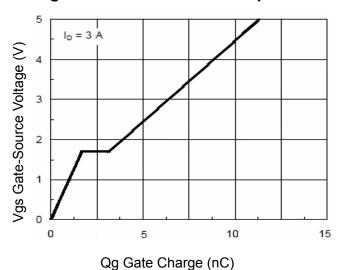
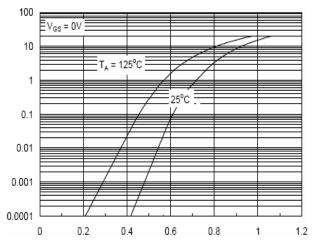


Figure 5 Gate Charge



Vsd Source-Drain Voltage (V)

Figure 6 Source- Drain Diode Forward



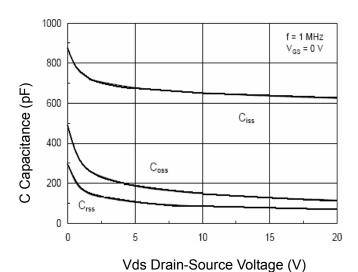


Figure 7 Capacitance vs Vds

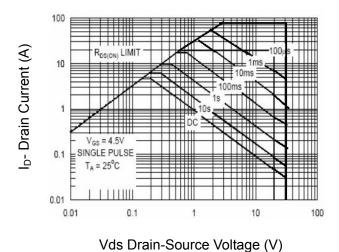
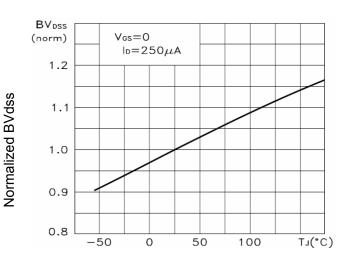


Figure 8 Safe Operation Area



 $T_J$ -Junction Temperature( ${}^{\circ}\mathbb{C}$ )

# Figure 9 BV<sub>DSS</sub> vs Junction Temperature

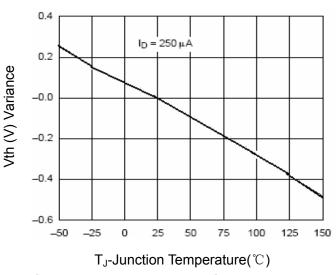


Figure 10 V<sub>GS(th)</sub> vs Junction Temperature

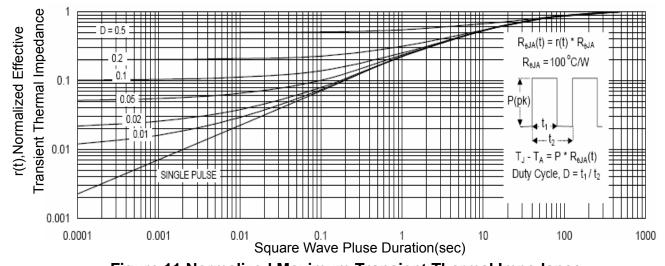
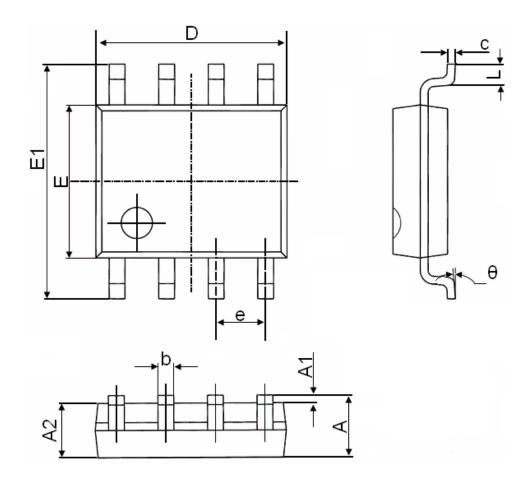


Figure 11 Normalized Maximum Transient Thermal Impedance



# **SOP-8 Package Information**



Combal	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
С	0.170	0.250	0.006	0.010	
D	4.700	5.100	0.185	0.200	
E	3.800	4.000	0.150	0.157	
E1	5.800	6.200	0.228	0.244	
е	1.270(BSC)		0.050(BSC)		
L	0.400	1.270	0.016	0.050	
θ	0°	8°	0°	8°	

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